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The invention relates to oxide semiconductor equipment and technology, in particular to methods for producing n-butanol sensors based on a ZnO-Al₂O₃ heterojunction.

The method, according to the invention, comprises the deposition of a nanostructured ZnO film on a glass substrate by chemical synthesis from a solution, deposition of a Al_2O_3 film on a ZnO film of a thickness of 17...20 nm, by vacuum thermal evaporation of aluminum triisopropylate $(Al(C_3H_7O)_3)$ at the substrate temperature of 450°C, deposition on the Al_2O_3 film of meander-shaped ohmic Au-Cr contacts, fast photon processing of the resulting structure at a temperature of 650°C for 30 s.

Claims: 1 Fig.: 3